



Patent
Attorney's Docket No. 007413-060

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of)	
)	
Wilfried CLAUSS)	Group Art Unit: Unassigned
)	
Application No.: 10/631,900)	Examiner: Unassigned
)	
Filed: August 1, 2003)	Confirmation No.: 9807
)	
For: PARTICLE-OPTICAL APPARATUS)	
AND METHOD FOR OPERATING THE)	
SAME)	

FIRST
INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure as set forth in 37 C.F.R. § 1.56, Applicant hereby submits the following information in conformance with 37 C.F.R. §§ 1.97 and 1.98.

Pursuant to 37 C.F.R. § 1.98, a copy of each of the documents cited is enclosed.

- 1) U.S. 4,246,128
- 2) U.S. 4,376,249
- 3) U.S. 4,817,706
- 4) U.S. 5,629,526
- 5) U.S. 5,738,949
- 6) U.S. 6,011,268
- 7) U.S. 6,188,071
- 8) U.S. 6,217,789
- 9) U.S. 6,297,634
- 10) U.S. 6,566,663
- 11) U.S. 2002/0084422
- 12) U.S. 2003/0066961

(09/03)

- 13) EP 0 461 366
- 14) DE 100 44 199
- 15) JP 64-017364 (also referred to as JP 01017364)
- 16) JP 2001230190
- 17) JP 2001307975
- 18) JP 2002170761
- 19) X. ZHU et al., "Comprehensive Analysis of Electron Optical Design of SCALPEL-HT/Alpha", Proc. SPIE, Vol. 3997, pp. 170-183, July 2000, Emerging Lithographic Technologies IV, Elizabeth A. Dobisz, Ed.
- 20) Eiichi GOTO et al., "*MOL (moving objective lens) Formulation of deflective aberration free system*," OPTIK, Vol. 48, No. 3, pp. 255-270 (1977), Wissenschaftliche Verlagsgesellschaft mbH, Stuttgart, Germany.

The documents are being submitted within three (3) months of the filing or entry of the national stage of this application or before the first Office Action on the merits, whichever is later. Since documents are being filed within the time period set forth in 37 C.F.R. § 1.97(b) no fee or statement is required.


Machine translations obtained from the Japan Patent Office website for three of the four above-noted Japanese patent documents for which machine translations are available (JP 2001230190, JP 2002170761, JP 2001307975) have also been provided, but the accuracy of these translations has not been verified.

Also, DE 100 44 199 is a foreign language document. Both this document, and U.S. Patent Application Publication No. 2002/0084422, are indicated on the faces thereof as corresponding to German Patent Application No. 100 44 199.8.

To assist the Examiner, the documents are listed on the attached form PTO-1449. It is respectfully requested that an Examiner-initialed copy of this form be returned to the undersigned.

Respectfully submitted,
BURNS, DOANE, SWECKER & MATHIS, L.L.P.

Date: November 20, 2003

By: 

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Substitute for forms 1449A/PTO & 1449B/PTO

**FIRST INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**ATTORNEY'S DKT No.
007413-060APPLICATION No.
10/631,900APPLICANT
Wilfried CLAUSSFILING DATE
August 1, 2003GROUP
Unassigned**U.S. PATENT DOCUMENTS**

Examiner Initials	Document Number	Kind Code (if known)	Name of Patentee or Applicant of Cited Document	Issue/Publication Date (MM-DD-YYYY)
	4,246,128		Gallagher et al.	01-20-1981
	4,376,249		Pfeiffer et al.	03-08-1983
	4,817,706		Miyama et al.	04-04-1989
	5,629,526		Nakasuji	05-13-1997
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	6,188,071	B1	Gordon et al.	02-13-2001
	6,217,789	B1	Inoue et al.	04-17-2001
	6,297,634	B1	Aoki	10-02-2001
	6,566,663	B1	Kamijo et al.	05-20-2003
	2002/0084422	A1	Kienzle et al.	07-04-2002
	2003/0066961	A1	Kienzle et al.	04-10-2003

FOREIGN PATENT DOCUMENTS

Examiner Initials	Document Number	Kind Code (if known)	Country	Date of Publication (MM-DD-YYYY)	Translation Yes	No
	0 461 366	A2	Europe	12-18-1991		
	100 44 199	A1	Germany	06-06-2002		X
	64-017364	A	Japan	01-20-1989	Abst	
	2001230190	A	Japan	08-24-2001	X	
	2002170761	A	Japan	06-14-2002	X	
	2001307975	A	Japan	11-02-2001	X	

NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Include name of author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
	X. ZHU et al., "Comprehensive Analysis of Electron Optical Design of SCALPEL-HT/Alpha", Proc. SPIE, Vol. 3997, pp. 170-183, July 2000, Emerging Lithographic Technologies IV, Elizabeth A. Dobisz, Ed.
	Eiichi GOTO et al., "MOL (moving objective lens) Formulation of deflective aberration free system," OPTIK, Vol.48, No. 3, pp. 255-270 (1977), Wissenschaftliche Verlagsgesellschaft mbH, Stuttgart, Germany.

Examiner Signature	Date Considered
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. **SEND TO:** Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.